



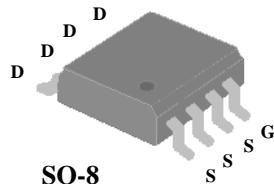
**Advanced Power
Electronics Corp.**

AP15P15GM-HF

Halogen-Free Product

**P-CHANNEL ENHANCEMENT MODE
POWER MOSFET**

- ▼ Lower Gate Charge
- ▼ Simple Drive Requirement
- ▼ Fast Switching Characteristic
- ▼ RoHS Compliant & Halogen-Free

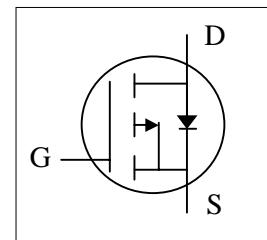


BV_{DSS}	-140V
$R_{DS(ON)}$	180mΩ
I_D	-2.7A

Description

Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SO-8 package is widely preferred for commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-140	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current ³	-2.7	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current ³	-2.1	A
I_{DM}	Pulsed Drain Current ¹	-20	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation	2.5	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient ³	50	°C/W



Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=-250\mu\text{A}$	-140	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=-10\text{V}$, $I_{\text{D}}=-2\text{A}$	-	-	180	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{D}}=-250\mu\text{A}$	-1	-	-3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-10\text{V}$, $I_{\text{D}}=-2\text{A}$	-	11	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=-120\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-25	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}= \pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_{\text{D}}=-2\text{A}$	-	51	80	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=-70\text{V}$	-	6	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-10\text{V}$	-	12	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ²	$V_{\text{DS}}=-70\text{V}$	-	12	-	ns
t_r	Rise Time	$I_{\text{D}}=-2\text{A}$	-	8.5	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega$, $V_{\text{GS}}=-10\text{V}$	-	83	-	ns
t_f	Fall Time	$R_D=35\Omega$	-	35	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	2850	4560	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=-25\text{V}$	-	150	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	100	-	pF
R_g	Gate Resistance	f=1.0MHz	-	6.6	-	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_{\text{S}}=-2\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	-1.3	V
t_{rr}	Reverse Recovery Time ²	$I_{\text{S}}=-2\text{A}$, $V_{\text{GS}}=0\text{V}$,	-	46	-	ns
Q_{rr}	Reverse Recovery Charge	$dI/dt=-100\text{A}/\mu\text{s}$	-	106	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² copper pad of FR4 board ; 125 °C/W when mounted on Min. copper pad.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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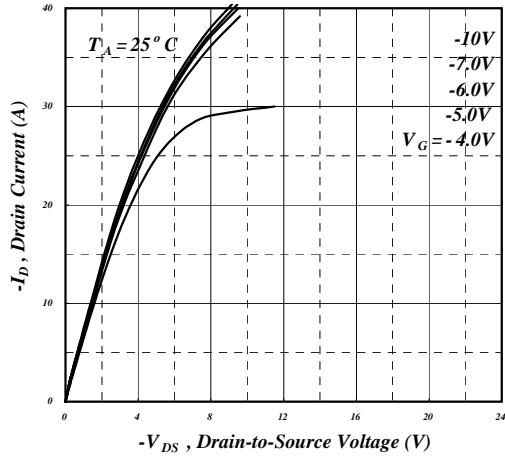


Fig 1. Typical Output Characteristics

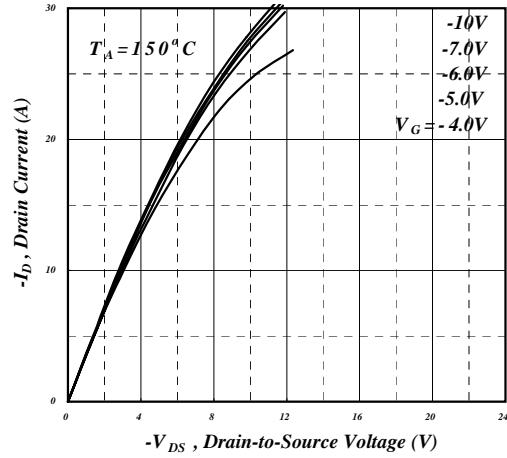


Fig 2. Typical Output Characteristics

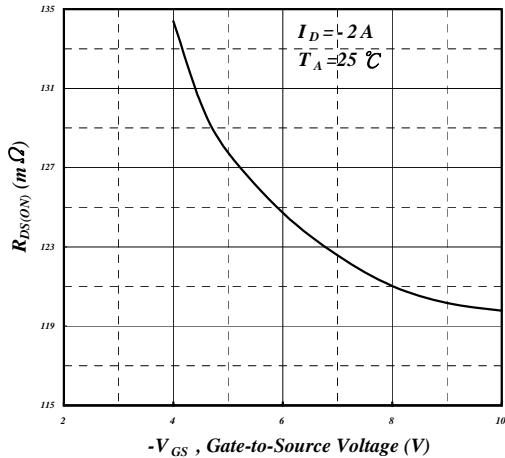


Fig 3. On-Resistance v.s. Gate Voltage

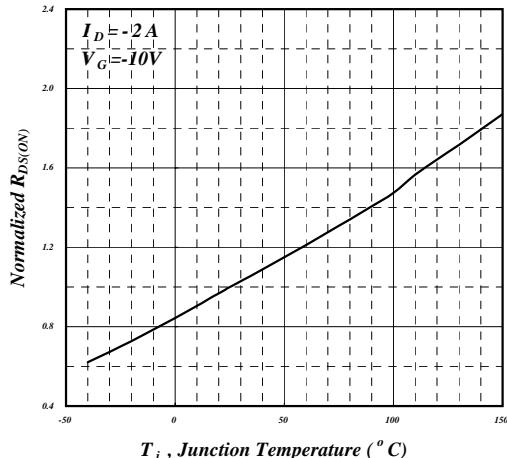


Fig 4. Normalized On-Resistance v.s. Junction Temperature

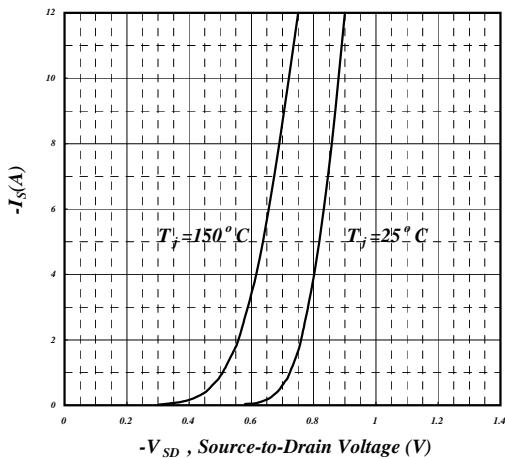


Fig 5. Forward Characteristic of Reverse Diode

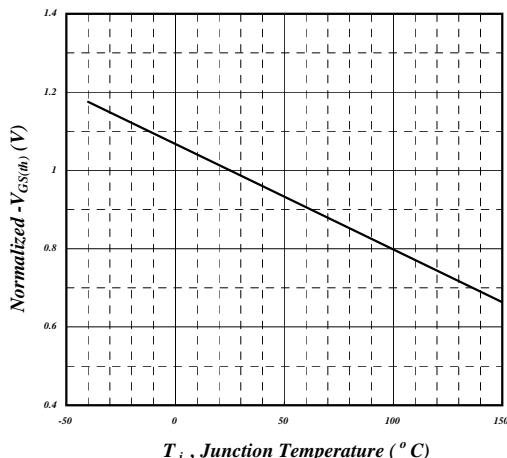


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

